

Notice of References Cited	Application/Control No. 10/825,433	Applicant(s)/Patent Under Reexamination LEE, YUN BOK	
	Examiner James A. Dudek	Art Unit 2871	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2005/0128406	06-2005	Lee, Yun-Bok	349/141
	C	US-2005/0128405	06-2005	Lee, Yun-Bok	349/141
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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